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Sheet 2 of 2

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO 1072-2495		PRIORITY SERIAL NO 10/820,575	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Sean E. Moore et al		PRIORITY FILING DATE March 7, 2006	
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U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
/RMP/	AI	"The Science and Engineering of Microelectronic Fabrication" Campbell, Stephen A.; Oxford University Press: 1996, pp. 212-237.					
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